Search Notes



Application/Control No.	No. Applicant(s)/Patent under Reexamination	
10/623,026	LEE ET AL.	
Examiner	Art Unit	
Tuan V. Thai	2186	

SEARCHED					
Class	Subclass	Date	Examiner		
711	5	7/19/2006	тн		
711	100	7/19/2006	тн		
711	154	7/19/2006	тн		
711	170	7/19/2006	ТН		
711	200	7/19/2006	ТН		
370	395.7	7/19/2006	тн		
370	412	7/19/2006	ТН		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
711	5	7/19/2006	тн		
370	395.7	7/19/2006	ТН		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
IEEE updated search; NPL search; EAST updated searches: IBMTDB DERWENTS EPO/JPO abstract USPGPUB	7/19/2006	тн		
NORHT database				
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